



OMB No. 0651-0011

## INFORMATION DISCLOSURE CITATION

Patent No.	0001	Appl. No.	10/765,671
Applicant	Hack, Jonathan A.		
Filing Date	January 26, 2004	Group:	2815

## U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
	6,469,605	Oct. 22, 2002	Hack et al.	335	297	June 1, 2001
	6,113,746	Sept. 5, 2000	Hack et al.	204	157.74	Nov. 26, 1997
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Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	Khokhlov et al., "Ferromagnetism induced in silicon by radiation defects," <i>JETP Lett.</i> , Vol. 24, No. 4, 20 August 1976, 211-213 (1976).
	Demidov et al., "Temperature Dependence of the ESR Signal of Radiation Defects in Silicon," <i>Sov. Phys. Semicond.</i> , Vol. 11, No. 4, April 1977, 459-460 (1977).
	Hack et al., "Ferromagnetic Properties of Spark-Processed Photoluminescing Silicon," <i>Mat. Res. Soc. Symp. Proc.</i> Vol. 452, 147-152 (1997).

Examiner	Date Considered 5/05
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
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